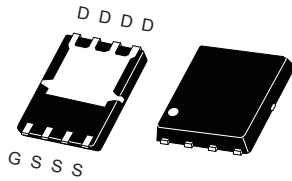


N-Channel Enhancement Mode Field Effect Transistor

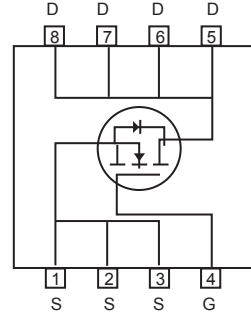
PRELIMINARY

FEATURES

- 30V, 85A, $R_{DS(ON)} = 4.0m\Omega$ @ $V_{GS} = 10V$.
 $R_{DS(ON)} = 6.0m\Omega$ @ $V_{GS} = 4.5V$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability.
- Lead free product is acquired.
- Surface mount Package.



PR-PACK (5*6)



ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	85	A
Drain Current-Pulsed ^a	I_{DM}	340	A
Maximum Power Dissipation	P_D	48	W
Single Pulsed Avalanche Energy ^e	E_{AS}	125	mJ
Single Pulsed Avalanche Current ^e	I_{AS}	50	A
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	2.6	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient ^b	$R_{\theta JA}$	20	C/W



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Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units	
Off Characteristics							
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	30			V	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V$			1	μA	
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{GS} = 20V, V_{DS} = 0V$			100	nA	
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{GS} = -20V, V_{DS} = 0V$			-100	nA	
On Characteristics ^c							
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1		3	V	
Static Drain-Source	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 18A$		3.0	4.0	m Ω	
On-Resistance		$V_{GS} = 4.5V, I_D = 15A$		4.0	6.0	m Ω	
Gate input resistance	R_g	f=1MHz, open Drain		1.8		Ω	
Dynamic Characteristics ^d							
Input Capacitance	C_{iss}	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1.0 \text{ MHz}$		2470		pF	
Output Capacitance	C_{oss}				325		pF
Reverse Transfer Capacitance	C_{rss}				185		pF
Switching Characteristics ^d							
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15V, I_D = 10A,$ $V_{GS} = 10V, R_{GEN} = 1\Omega$		26	52	ns	
Turn-On Rise Time	t_r			14	28	ns	
Turn-Off Delay Time	$t_{d(off)}$			67	134	ns	
Turn-Off Fall Time	t_f			9	18	ns	
Total Gate Charge	Q_g	$V_{DS} = 15V, I_D = 10A,$ $V_{GS} = 10V$		63	82	nC	
Gate-Source Charge	Q_{gs}			8		nC	
Gate-Drain Charge	Q_{gd}			15		nC	
Drain-Source Diode Characteristics and Maximum Ratings							
Drain-Source Diode Forward Current ^b	I_S				85	A	
Drain-Source Diode Forward Voltage ^c	V_{SD}	$V_{GS} = 0V, I_S = 18A$			1.2	V	
Notes : <input type="checkbox"/> a.Repetitive Rating : Pulse width limited by maximum junction temperature. <input type="checkbox"/> b.Surface Mounted on FR4 Board, $t \leq 10 \text{ sec.}$ <input type="checkbox"/> c.Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$. <input type="checkbox"/> d.Guaranteed by design, not subject to production testing. <input type="checkbox"/> e.L = 0.1mH, $I_{AS} = 50A, V_{DD} = 24V, R_G = 25\Omega, \text{Starting } T_J = 25 \text{ C}$							



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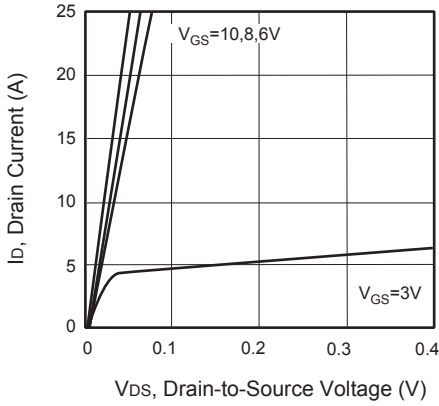


Figure 1. Output Characteristics

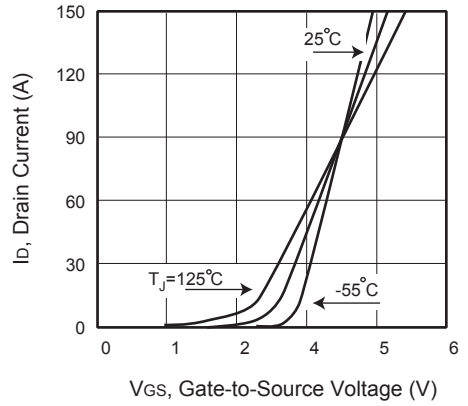


Figure 2. Transfer Characteristics

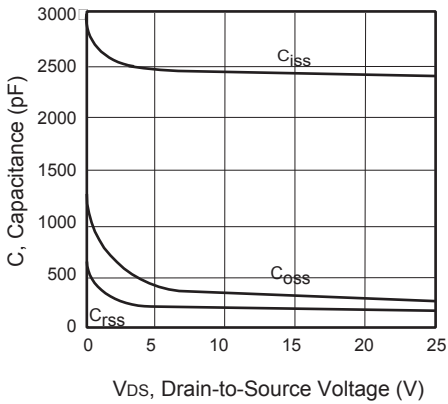


Figure 3. Capacitance

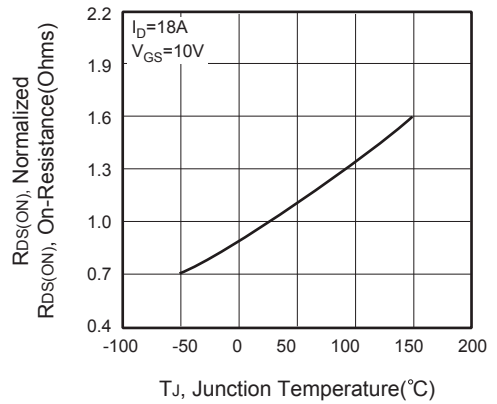


Figure 4. On-Resistance Variation with Temperature



Figure 5. Gate Threshold Variation with Temperature

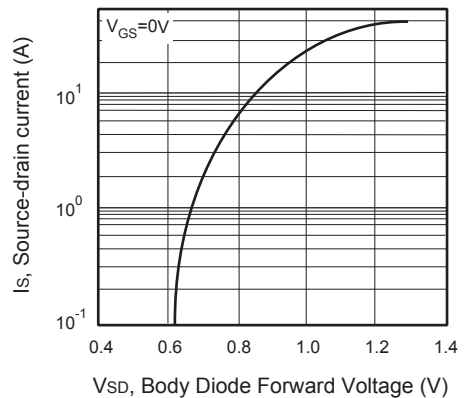


Figure 6. Body Diode Forward Voltage Variation with Source Current



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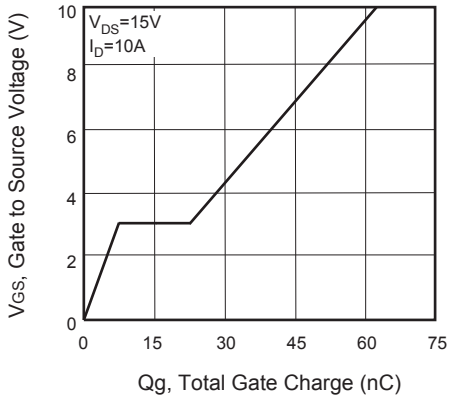


Figure 7. Gate Charge

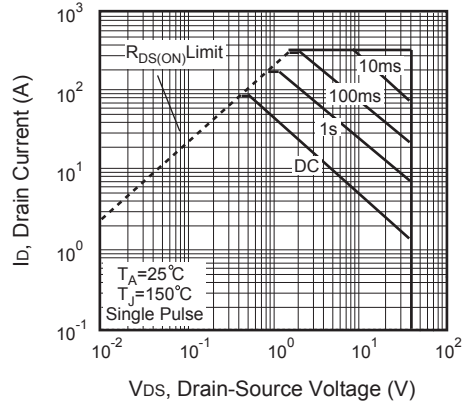


Figure 8. Maximum Safe Operating Area



Figure 9. Switching Test Circuit



Figure 10. Switching Waveforms

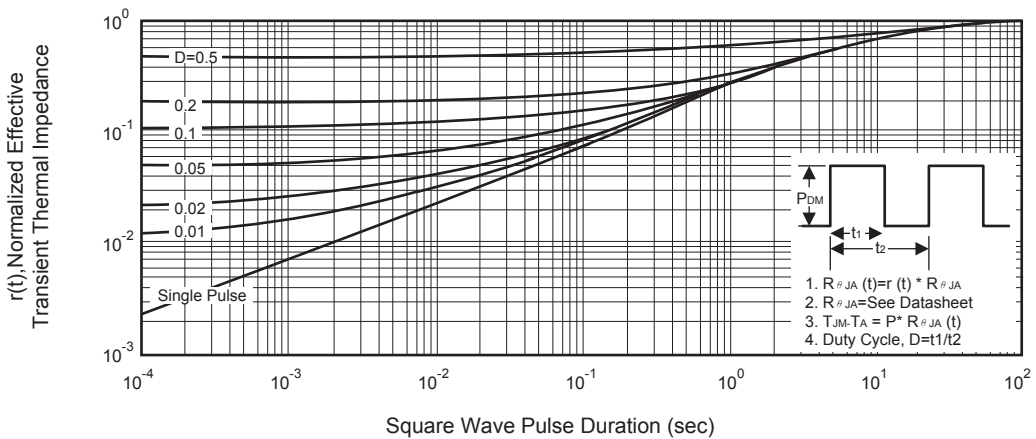


Figure 11. Normalized Thermal Transient Impedance Curve